1M x 4bit CMOS Quad CAS DRAM with Extended Data Out

DESCRIPTION

This is a family of 1,048,576 x 4bit Extended Data Out Quad CAS CMOS DRAMs. Extended Data Out offers high speed random access of memory cells within the same row. Access time (-5, -6 or -7), power consumption(Normal), and package type (SOJ or TSOP-II) are optional features of this family. All of this family have $\overline{CAS}$-before-$\overline{RAS}$ refresh, $\overline{RAS}$-only refresh and Hidden refresh capabilities. Furthermore, Self-refresh operation is available in Low power version. Four seperate $\overline{CAS}$ pins provide for seperate I/O operation allowing this device to operate in parity mode. This 1Mx4 Extended Data Out DRAM family is fabricated using Samsung′s advanced CMOS process to realize high band-width, low power consumption and high reliability.

FEATURES

- **Part Identification**

  - KM44C1005D(5V, 1K Ref.)

- **Active Power Dissipation**

Unit : mW

Speed	Active power dissipation
-5	468
-6	413
-7	358

- **Refresh Cycles**

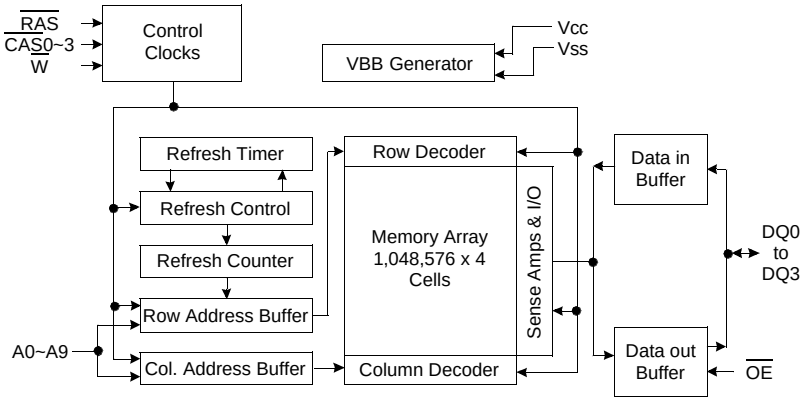
Part NO.	Refresh cycle	Refresh Period
		Normal
KM44C1005D	1K	16ms

- **Performance Range**

Speed	t_{RAC}	t_{CAC}	t_{RC}	t_{HPC}
-5	50ns	15ns	84ns	20ns
-6	60ns	15ns	104ns	25ns
-7	70ns	20ns	124ns	30ns

- Extended Data Out mode operation (Fast Page Mode with Extended data out)
- Four seperate $\overline{CAS}$ pins provide for seperate I/O operation
- $\overline{CAS}$-before-$\overline{RAS}$ refresh capability
- $\overline{RAS}$-only and Hidden refresh capability
- Self-refresh capability (L-ver only)
- Fast parallel test mode capability
- TTL compatible inputs and outputs
- Early Write or output enable controlled write
- JEDEC Standard pinout
- Available in 26(24)-pin SOJ 300mil and TSOP(II) 300mil packages
- Single +5V±10% power supply

FUNCTIONAL BLOCK DIAGRAM



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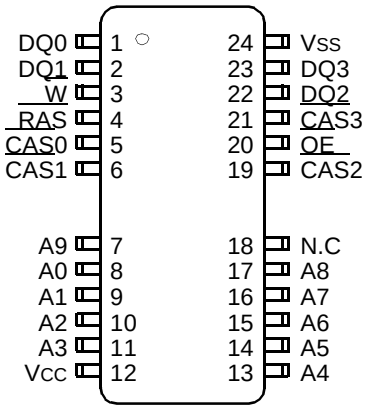
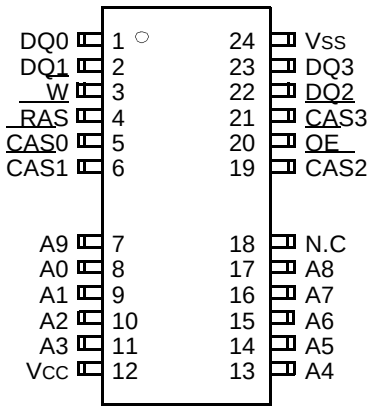
PIN CONFIGURATION (Top Views)

• **KM44C1005DJ**



(SOJ)

• **KM44C1005DT**



(TSOP-II)

Pin Name	Pin function
A0 - A9	Address Inputs
DQ0 - 3	Data In/Out
Vss	Ground
$\overline{RAS}$	Row Address Strobe
$\overline{CAS}$0~$\overline{CAS}$3	Column Address Strobe
$\overline{W}$	Read/Write Input
$\overline{OE}$	Data Output Enable
Vcc	Power(+5.0V)
N.C	No Connection

ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Rating	Units
Voltage on any pin relative to V_{SS}	V_{IN},V_{OUT}	-1 to +7.0	V
Voltage on V_{CC} supply relative to V_{SS}	V_{CC}	-1 to +7.0	V
Storage Temperature	Tstg	-55 to +150	°C
Power Dissipation	P_D	1	W
Short Circuit Output Current	I_{OS} Address	50	mA

* Permanent device damage may occur if "ABSOLUTE MAXIMUM RATINGS" are exceeded. Functional operation should be restricted to the conditions as detailed in the operational sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS (Voltage referenced to Vss, T_A= 0 to 70°C)

Parameter	Symbol	Rating	Typ	Max	Units
Supply Voltage	V_{CC}	4.5	5.0	5.5	V
Ground	V_{SS}	0	0	0	V
Input High Voltage	V_{IH}	2.4	-	V_{CC}+1.0*1	V
Input Low Voltage	V_{IL}	-1.0*2	-	0.8	V

*1 : V_{CC} +2.0V at pulse width≤20ns, Pulse width is measured at V_{CC}
*2 : - 2.0V at pulse width≤20ns, Pulse width is measured at V_{SS}

DC AND OPERATING CHARACTERISTICS (Recommended operating conditions unless otherwise noted.)

Parameter	Symbol	Min	Max	Units
Input Leakage Current (Any input 0≤V_{IN}≤V_{CC}+0.5V, all other input pins not under test=0 Volt)	$I_{I(L)}$	-5	5	uA
Output Leakage Current (Data out is disabled, 0V≤V_{OUT}≤V_{CC})	$I_{O(L)}$	-5	5	uA
Output High Voltage Level(I_{OH}=-5mA)	V_{OH}	2.4	-	V
Output Low Voltage Level(I_{OL}=4.2mA)	V_{OL}	-	0.4	V

DC AND OPERATING CHARACTERISTICS (Continued)

Symbol	Power	Speed	Max	Units
			KM44C1005D	
I_{CC1}	Don't Care	-5 -6 -7	85 75 65	mA mA mA
I_{CC2}	Don't Care	Don't Care	2	mA
I_{CC3}	Don't Care	-5 -6 -7	85 75 65	mA mA mA
I_{CC4}	Don't Care	-5 -6 -7	85 75 6	mA mA mA
I_{CC5}	Normal L	Don't Care	1 200	mA uA
I_{CC6}	Don't Care	-5 -6 -7	85 75 65	mA mA mA

I_{CC1}* : Operating Current ($\overline{RAS}$ and $\overline{CAS}$ cycling @t_{RC}=min.)

I_{CC2} : Standby Current ($\overline{RAS}$=$\overline{CAS}$=$\overline{W}$=V_{IH})

I_{CC3}* : $\overline{RAS}$-only Refresh Current ($\overline{CAS}$=V_{IH}, $\overline{RAS}$, Address cycling @t_{RC}=min.)

I_{CC4}* : EDO Mode Current ($\overline{RAS}$=V_{IL}, $\overline{CAS}$, Address cycling @t_{HPC}=min.)

I_{CC5} : Standby Current ($\overline{RAS}$=$\overline{CAS}$=$\overline{W}$=V_{CC}-0.2V)

I_{CC6}* : $\overline{CAS}$-Before-$\overline{RAS}$ Refresh Current ($\overline{RAS}$ and $\overline{CAS}$ cycling @t_{RC}=min)

***Note :** I_{CC1}, I_{CC3}, I_{CC4} and I_{CC6} are dependent on output loading and cycle rates. Specified values are obtained with the output open. I_{CC} is specified as an average current. In I_{CC1}, I_{CC3} and I_{CC6} address can be changed maximum once while $\overline{RAS}$=V_{IL}. In I_{CC4}, address can be changed maximum once within one hyper page cycle time, t_{HPC}.

CAPACITANCE (T_A=25°C, V_{CC}=5V, f=1MHz)

Parameter	Symbol	Min	Max	Units
Input capacitance [A0 ~ A9]	C_{IN1}	-	5	pF
Input capacitance [$\overline{RAS}$, $\overline{CAS}$, $\overline{W}$, $\overline{OE}$]	C_{IN2}	-	7	pF
Output capacitance [DQ0 - DQ3]	C_{DQ}	-	7	pF

AC CHARACTERISTICS ($0°C \le T_A \le 70°C$, See note 1,2)

Test condition : V_{CC}=5.0V±10%, Vih/Vil=2.4/0.8V, Voh/Vol=2.0/0.8V

Parameter	Symbol	-5		-6		7		Units	Notes
		Min	Max	Min	Max	Min	Max		
Random read or write cycle time	t_{RC}	84		104		124		ns	
Read-modify-write cycle time	t_{RWC}	116		138		163		ns	
Access time from $\overline{RAS}$	t_{RAC}		50		60		70	ns	3,4,10
Access time from $\overline{CAS}$	t_{CAC}		15		15		20	ns	3,4,5,22
Access time from column address	t_{AA}		25		30		35	ns	3,10
$\overline{CAS}$ to output in Low-Z	t_{CLZ}	3		3		3		ns	3,22
Output buffer turn-off delay from $\overline{CAS}$	t_{CEZ}	3	13	3	13	3	18	ns	6,13,22
Transition time (rise and fall)	t_T	2	50	2	50	2	50	ns	2
$\overline{RAS}$ precharge time	t_{RP}	30		40		50		ns	
$\overline{RAS}$ pulse width	t_{RAS}	50	10K	60	10K	70	10K	ns	
$\overline{RAS}$ hold time	t_{RSH}	15		15		20		ns	18
$\overline{CAS}$ hold time	t_{CSH}	40		50		60		ns	21
$\overline{CAS}$ pulse width	t_{CAS}	8	10K	10	10K	15	10K	ns	27
$\overline{RAS}$ to $\overline{CAS}$ delay time	t_{RCD}	20	35	20	45	20	50	ns	4,20
$\overline{RAS}$ to column address delay time	t_{RAD}	15	25	15	30	15	35	ns	10
$\overline{CAS}$ to $\overline{RAS}$ precharge time	t_{CRP}	5		5		5		ns	19
Row address set-up time	t_{ASR}	0		0		0		ns	
Row address hold time	t_{RAH}	10		10		10		ns	
Column address set-up time	t_{ASC}	0		0		0		ns	20
Column address hold time	t_{CAH}	8		10		15		ns	20
Column address to $\overline{RAS}$ lead time	t_{RAL}	25		30		35		ns	
Read command set-up time	t_{RCS}	0		0		0		ns	
Read command hold time referenced to $\overline{CAS}$	t_{RCH}	0		0		0		ns	8
Read command hold time referenced to $\overline{RAS}$	t_{RRH}	0		0		0		ns	8
Write command hold time	t_{WCH}	10		10		15		ns	28
Write command pulse width	t_{WP}	10		10		15		ns	
Write command to $\overline{RAS}$ lead time	t_{RWL}	15		15		15		ns	
Write command to $\overline{CAS}$ lead time	t_{CWL}	8		10		15		ns	21
Data set-up time	t_{DS}	0		0		0		ns	9
Data hold time	t_{DH}	8		10		15		ns	9

AC CHARACTERISTICS (Continued)

Parameter	Symbol	-5		-6		-7		Units	Notes
		Min	Max	Min	Max	Min	Max		
Refresh period (4K, Normal)	t_{REF}		16		16		16	ms	
Refresh period (L-ver)	t_{REF}		128		128		128	ms	
Write command set-up time	t_{WCS}	0		0		0		ns	7,20
$\overline{CAS}$ to $\overline{W}$ delay time	t_{CWD}	32		32		42		ns	7,20
$\overline{RAS}$ to $\overline{W}$ delay time	t_{RWD}	67		77		92		ns	7
Column address to $\overline{W}$ delay time	t_{AWD}	42		47		57		ns	7
$\overline{CAS}$ precharge to $\overline{W}$ delay time	t_{CPWD}	45		52		62		ns	7
$\overline{CAS}$ set-up time ($\overline{CAS}$ -before-$\overline{RAS}$ refresh)	t_{CSR}	5		5		5		ns	20
$\overline{CAS}$ hold time ($\overline{CAS}$ -before-$\overline{RAS}$ refresh)	t_{CHR}	10		10		15		ns	19
$\overline{RAS}$ to $\overline{CAS}$ precharge time	t_{RPC}	5		5		5		ns	
$\overline{CAS}$ precharge time ($\overline{C}$-B-$\overline{R}$ counter test cycle)	t_{CPT}	20		20		25		ns	
Access time from $\overline{CAS}$ precharge	t_{CPA}		28		35		40	ns	3,20
Hyper Page mode cycle time	t_{HPC}	20		25		30		ns	15,23
Hyper Page read-modify-write cycle time	t_{HPRWC}	57		66		81		ns	23
$\overline{CAS}$ precharge time (Hyper Page cycle)	t_{CP}	8		10		10		ns	24
$\overline{RAS}$ pulse width (Hyper Page cycle)	t_{RASP}	50	200K	60	200K	70	200K	ns	
$\overline{RAS}$ hold time from $\overline{CAS}$ precharge	t_{RHCP}	30		35		40		ns	
$\overline{OE}$ access time	t_{OEA}		15		15		20	ns	25
$\overline{OE}$ to data delay	t_{OED}	13		13		18		ns	25
Output buffer turn off delay time from $\overline{OE}$	t_{OEZ}	3	13	3	13	3	18	ns	6,13
$\overline{OE}$ to output in low-Z	t_{OLZ}	3		3		3			
$\overline{OE}$ command hold time	t_{OEH}	15		15		20		ns	
Output data hold time	t_{DOH}	5		5		5		ns	
Output buffer turn off delay time from $\overline{RAS}$	t_{REZ}	3	15	3	15	3	20	ns	6,13
Output buffer turn off delay time from $\overline{W}$	t_{WEZ}	3	13	3	13	3	18	ns	6,13
$\overline{W}$ to data delay	t_{WED}	13		13		18		ns	
$\overline{OE}$ to $\overline{CAS}$ hold time	t_{OCH}	5		5		5		ns	
$\overline{CAS}$ hold time to $\overline{OE}$	t_{CHO}	5		5		5		ns	
$\overline{OE}$ precharge time	t_{OEP}	5		5		5		ns	
$\overline{W}$ pulse width (hyper page cycle)	t_{WPE}	5		5		5		ns	
Write command set-up time (Test mode in)	t_{WTS}	10		10		10		ns	
Write command hold time (Test mode in)	t_{WTH}	10		10		10		ns	
$\overline{W}$ to $\overline{RAS}$ prechrge time ($\overline{C}$-B-$\overline{R}$ refresh)	t_{WRP}	10		10		10		ns	
$\overline{W}$ to $\overline{RAS}$ hold time ($\overline{C}$-B-$\overline{R}$ refresh)	t_{WRH}	10		10		10		ns	
Hold time $\overline{CAS}$ low to $\overline{CAS}$ high	t_{CLCH}	5		5		5		ns	16,28

TEST MODE CYCLE

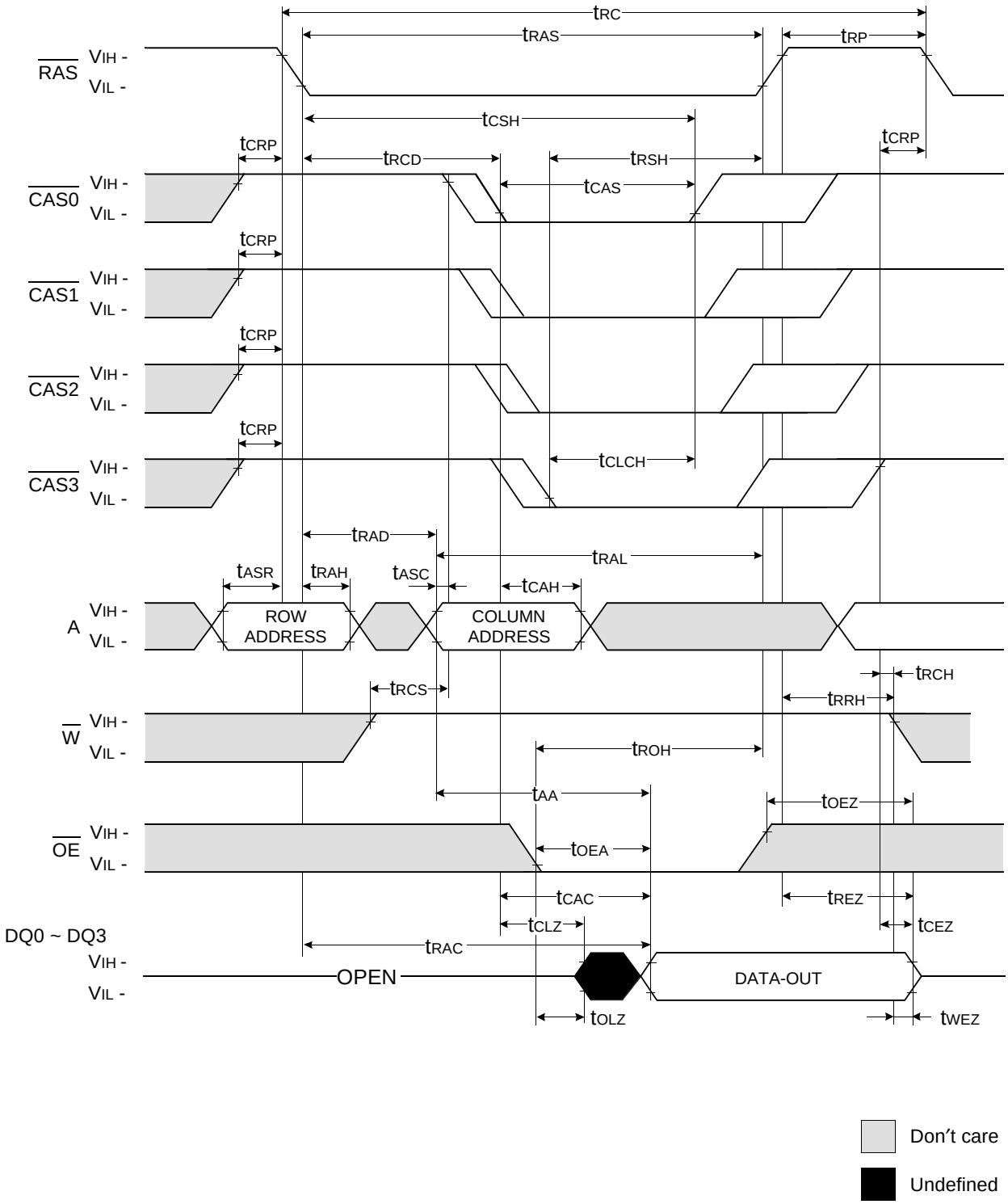
(Note 11)

Parameter	Symbol	-5		-6		-7		Units	Notes
		Min	Max	Min	Max	Min	Max		
Random read or write cycle time	t_{RC}	89		109		129		ns	
Read-modify-write cycle time	t_{RWC}	121		145		170		ns	
Access time from $\overline{RAS}$	t_{RAC}		55		65		75	ns	3,4,10,12
Access time from $\overline{CAS}$	t_{CAC}		18		20		25	ns	3,4,5,12
Access time from column address	t_{AA}		30		35		40	ns	3,10,12
$\overline{RAS}$ pulse width	t_{RAS}	55	10K	65	10K	75	10K	ns	
$\overline{CAS}$ pulse width	t_{CAS}	13	10K	15	10K	20	10K	ns	
$\overline{RAS}$ hold time	t_{RSH}	18		20		25		ns	
$\overline{CAS}$ hold time	t_{CSH}	45		55		65		ns	
Column Address to $\overline{RAS}$ lead time	t_{RAL}	30		35		40		ns	
$\overline{CAS}$ to $\overline{W}$ delay time	t_{CWD}	35		39		49		ns	7
$\overline{RAS}$ to $\overline{W}$ delay time	t_{RWD}	72		84		94		ns	7
Column Address to $\overline{W}$ delay time	t_{AWD}	47		54		64		ns	7
Hyper Page mode cycle time	t_{HPC}	25		30		35		ns	
Hyper Page mode read-modify-write cycle	t_{HPRWC}	52		61		76		ns	
$\overline{RAS}$ pulse width (Fast Page cycle)	t_{RASP}	55	200K	65	200K	75	200K	ns	
Access time from $\overline{CAS}$ precharge	t_{CPA}		33		40		45	ns	3
$\overline{OE}$ access time	t_{OEA}		18		20		25	ns	
$\overline{OE}$ to data delay	t_{OED}	18		20		25		ns	
$\overline{OE}$ command hold time	t_{OEH}	18		20		25		ns	

NOTES

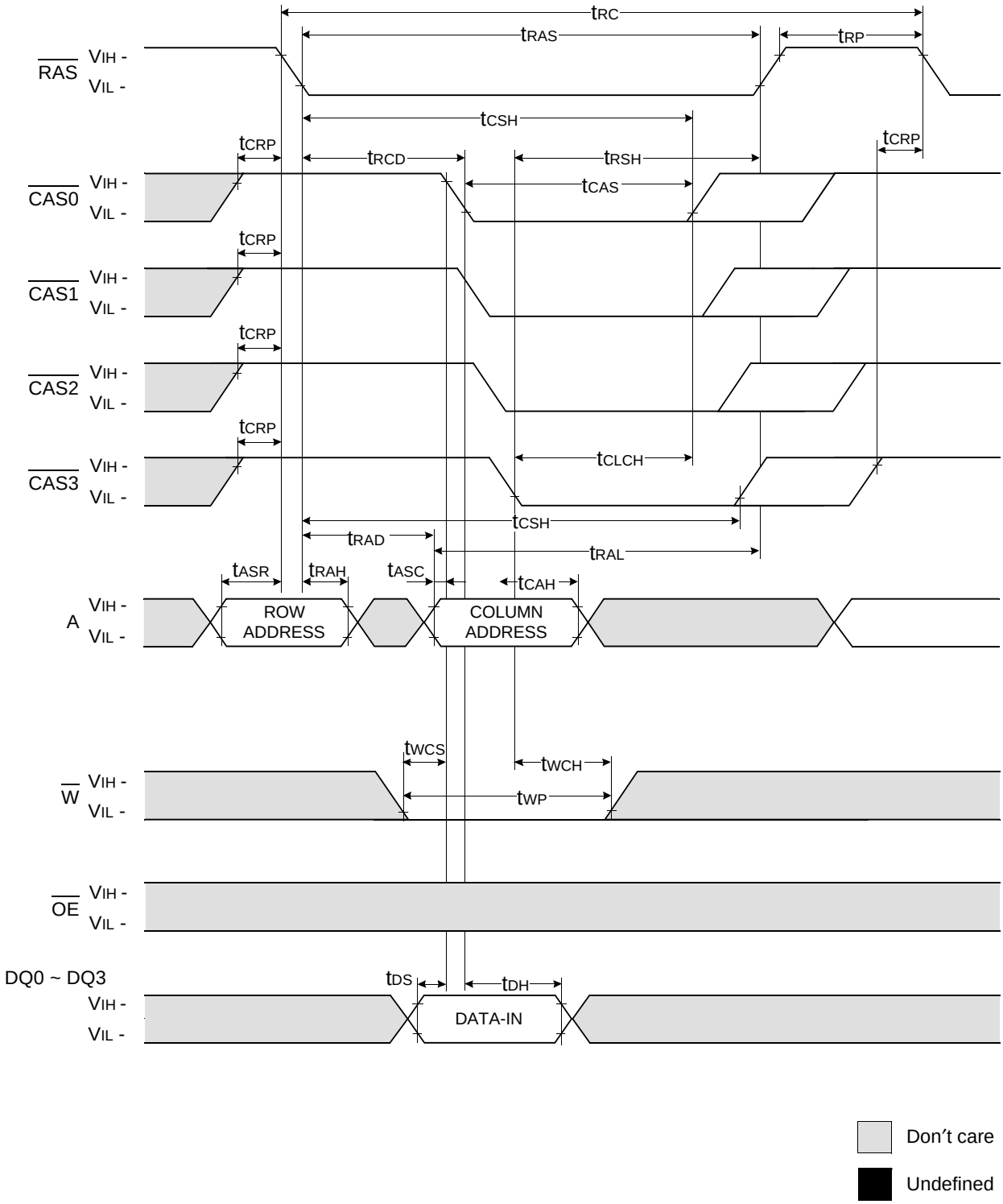
1. An initial pause of 200us is required after power-up followed by any 8 $\overline{RAS}$-only refresh or $\overline{CAS}$-before-$\overline{RAS}$ refresh cycles before proper device operation is achieved.
2. V_{IH}(min) and V_{IL}(max) are reference levels for measuring timing of input signals.
   Transition times are measured between V_{IH}(min) and V_{IL}(max) and are assumed to be 2ns for all inputs.
3. Measured with a load equivalent to 2 TTL load and 100pF.
4. Operation within the t_{RCD}(max) limit insures that t_{RAC}(max) can be met. t_{RCD}(max) is specified as a reference point only.
   If t_{RCD} is greater than the specified t_{RCD}(max) limit, then access time is controlled exclusively by t_{CAC}.
5. Assumes that $t_{RCD} \geq t_{RCD}$(max).
6. This parameter defines the time at which the output achieves the open circuit condition and is not referenced to V_{oh} or V_{ol}.
7. t_{WCS}, t_{RWD}, t_{CWD}, t_{AWD} and t_{CPWD} are non restrictive operating parameters. They are included in the data sheet as electrical characteristics only. If $t_{WCS} \geq t_{WCS}$(min), the cycle is an early write cycle and the data output will remain high impedance for the duration of the cycle. If $t_{CWD} \geq t_{CWD}$(min), $t_{RWD} \geq t_{RWD}$(min), $t_{AWD} \geq t_{AWD}$(min) and $t_{CPWD} \geq t_{CPWD}$(min) then the cycle is a read-modify-write cycle and the data output will contain the data read from the selected address. If neither of the above conditions is satisfied, the condition of the data out is indeterminate.
8. Either t_{RCH} or t_{RRH} must be satisfied for a read cycle.
9. These parameters are referenced to the first $\overline{CAS}$ falling edge in early write cycles and to $\overline{W}$ falling edge in $\overline{OE}$ controlled write cycle and read-modify-write cycles.
10. Operation within the t_{RAD}(max) limit insures that t_{RAC}(max) can be met. t_{RAD}(max) is specified as a reference point only.
    If t_{RAD} is greater than the specified t_{RAD}(max) limit, then access time is controlled by t_{AA}.
11. These specifiecations are applied in the test mode.
12. In test mode read cycle, the value of t_{RAC}, t_{AA}, t_{CAC} is delayed by 2ns to 5ns for the specified values. These parameters should be specified in test mode cycles by adding the above value to the specified value in this data sheet.
13. $t_{CEZ(MAX)}$, $t_{REZ(MAX)}$, $t_{OEZ(MAX)}$ and $t_{WEZ(MAX)}$ define the time at which the output achieves the open circuit condition and are not referenced to output voltage level.
14. If $\overline{RAS}$ goes high before $\overline{CAS}$ high going, the open circuit condition of the output is achieved by $\overline{CAS}$ high going.
    If $\overline{CAS}$ goes high before $\overline{RAS}$ high going, the open circuit condition of the output is achieved by $\overline{RAS}$ high going.
15. $t_{ASC} \geq 6.0$ns, Assumes $t_T = 2.0$ns
16. In order to hold the address latched by the first $\overline{CAS}$x going low, the parameter t_{CLCH} must be met.
17. If at least one $\overline{CAS}$ is low at the falling edge of $\overline{RAS}$, DQ will be maintained from the previous cycle.
    To initiate a new cycle and clear the data out buffer, all four $\overline{CAS}$ must be pulsed high for t_{CP}.
18. The last $\overline{CAS}$x edge to go low.
19. The last $\overline{CAS}$x edge to go high.
20. The first $\overline{CAS}$x edge to go low.
21. The first $\overline{CAS}$x edge to go high.
22. Output parameter is referenced to corresponding $\overline{CAS}$x Input.
23. The last rising $\overline{CAS}$x edge to next cycle's last rising $\overline{CAS}$x edge.
24. The last rising $\overline{CAS}$x edge to first falling $\overline{CAS}$x edge.
25. The first DQx controlled by the first $\overline{CAS}$x to go low.
26. The last DQx controlled by the first $\overline{CAS}$x to go high.
27. Each $\overline{CAS}$x must meet minimum pulse width.
28. The last falling $\overline{CAS}$x edge to the first rising $\overline{CAS}$x edge.

READ CYCLE


tRC
tRAS
tRP
RAS
VIH -
VIL -
tCSH
tCRP
tRCD
tRSH
tCAS
CAS0
CAS1
CAS2
CAS3
tCLCH
tRAD
tRAL
tASR
tRAH
tASC
tCAH
A
ROW ADDRESS
COLUMN ADDRESS
tRCS
tRCH
tRRH
W
tROH
tAA
tOEZ
OE
tOEA
tCAC
tREZ
tCLZ
tCEZ
DQ0 ~ DQ3
tRAC
OPEN
DATA-OUT
tOLZ
tWEZ
Don't care
Undefined

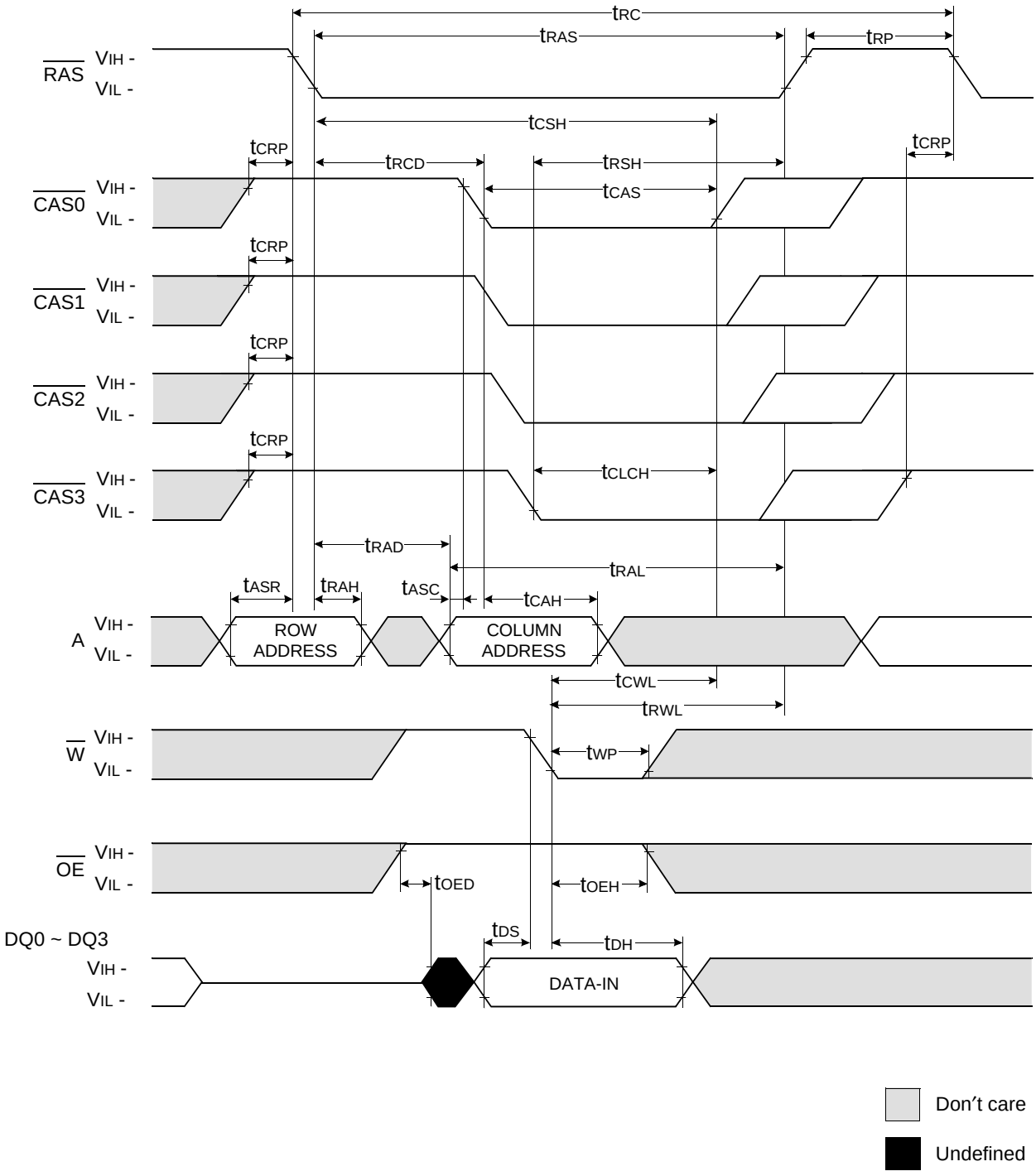
WRITE CYCLE (EARLY WRITE)

NOTE : DOUT = OPEN

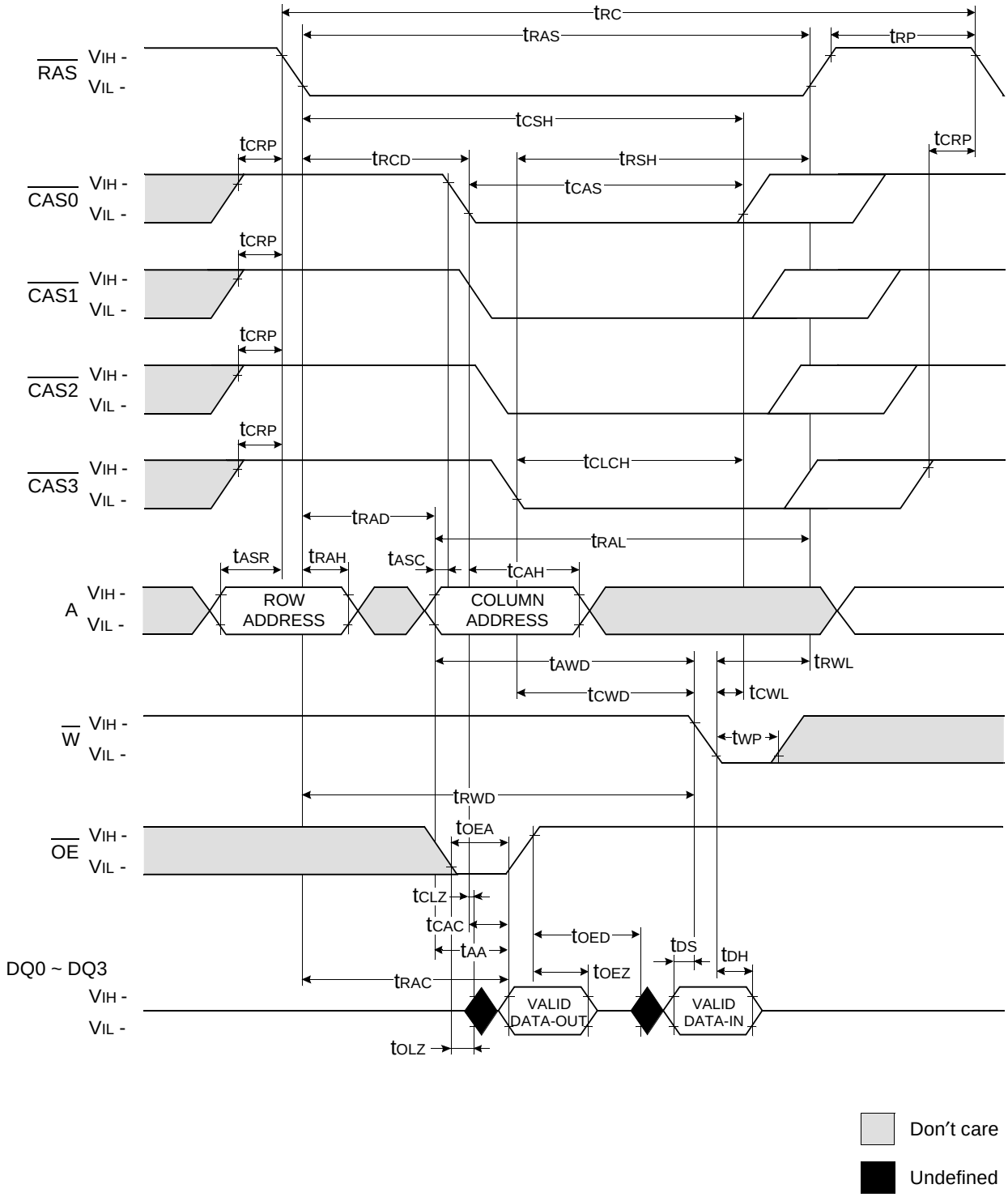


WRITE CYCLE ($\overline{OE}$ CONTROLLED WRITE)

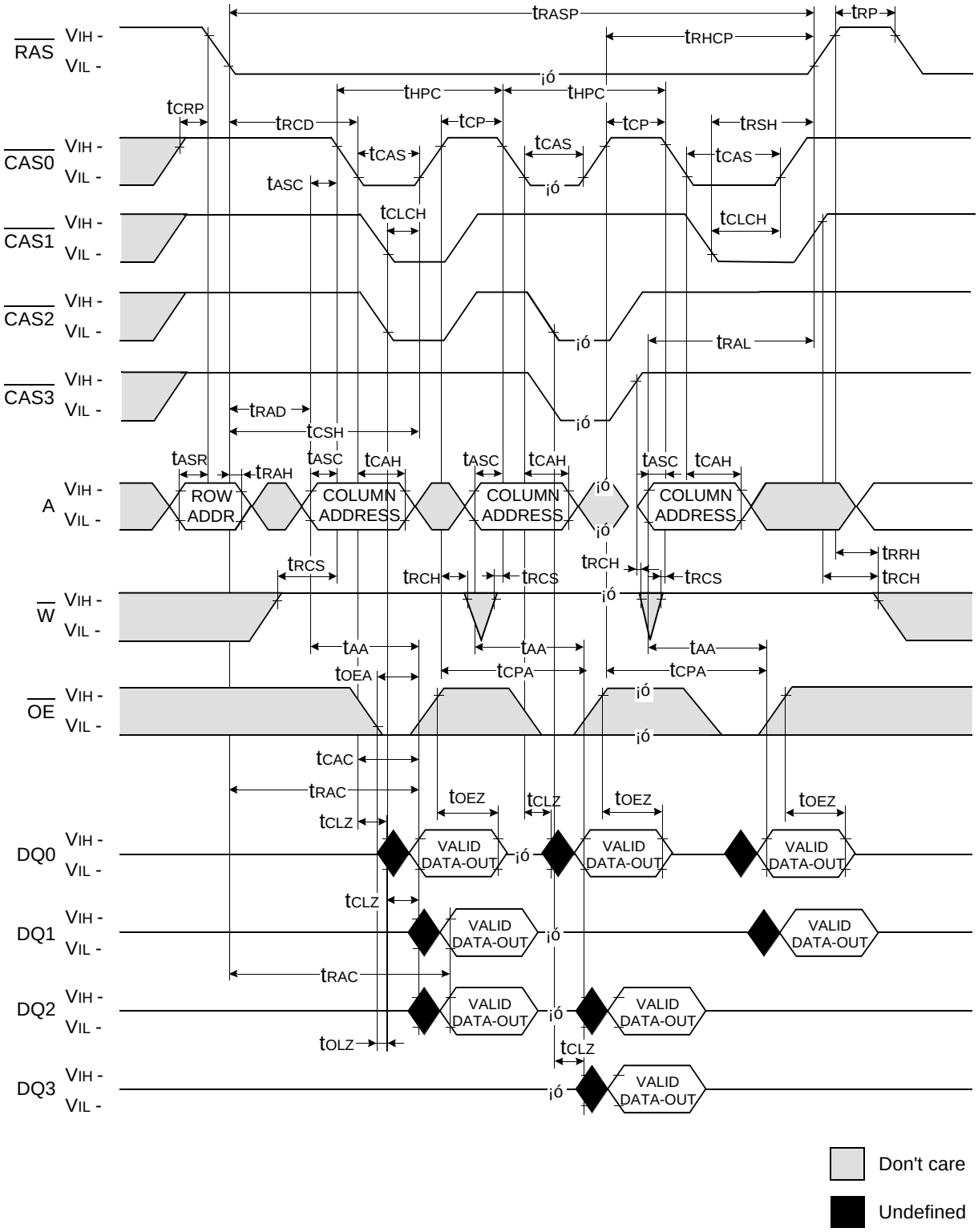
NOTE : DOUT = OPEN



READ - MODIFY - WRTIE CYCLE

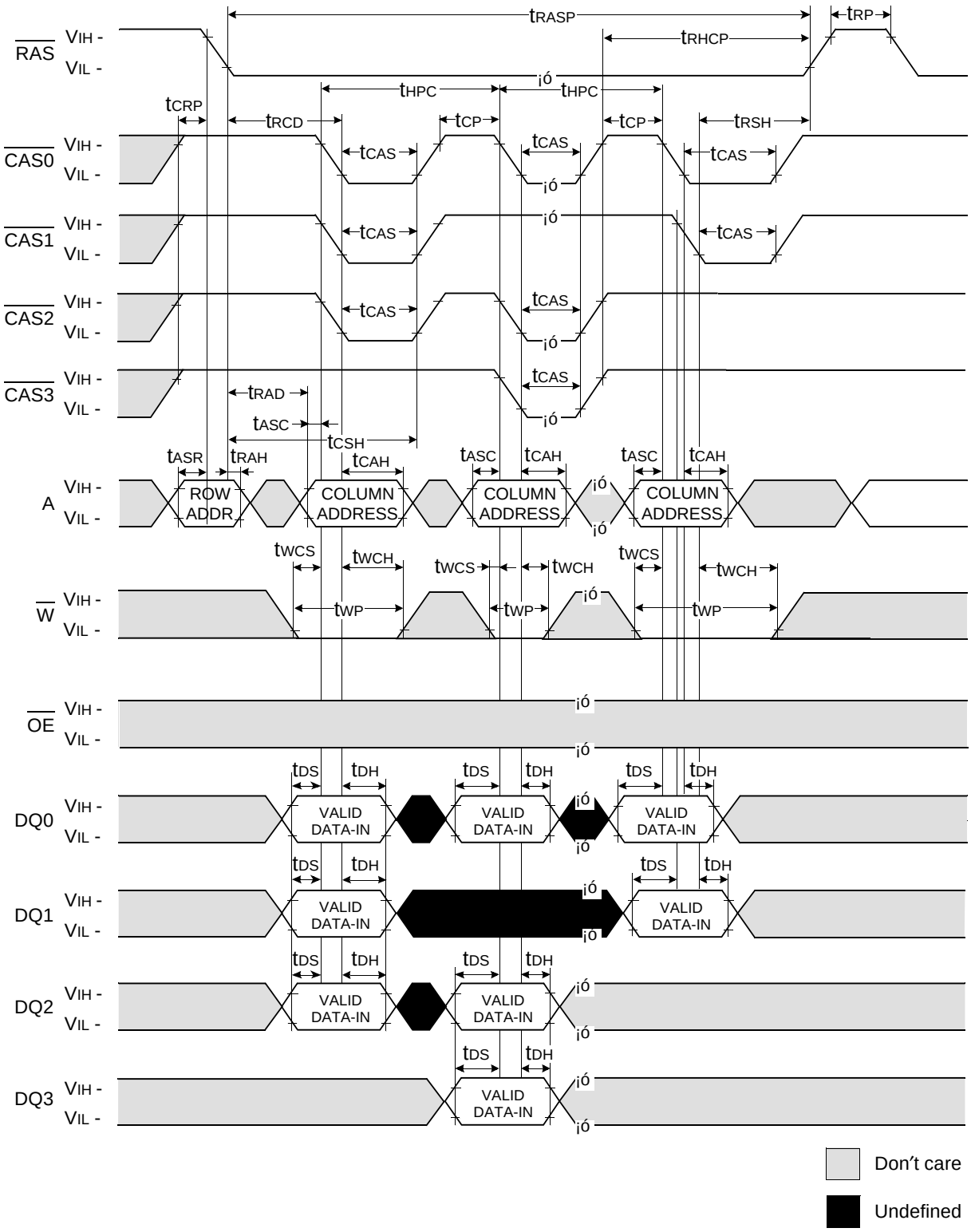


HYPER PAGE MODE READ CYCLE

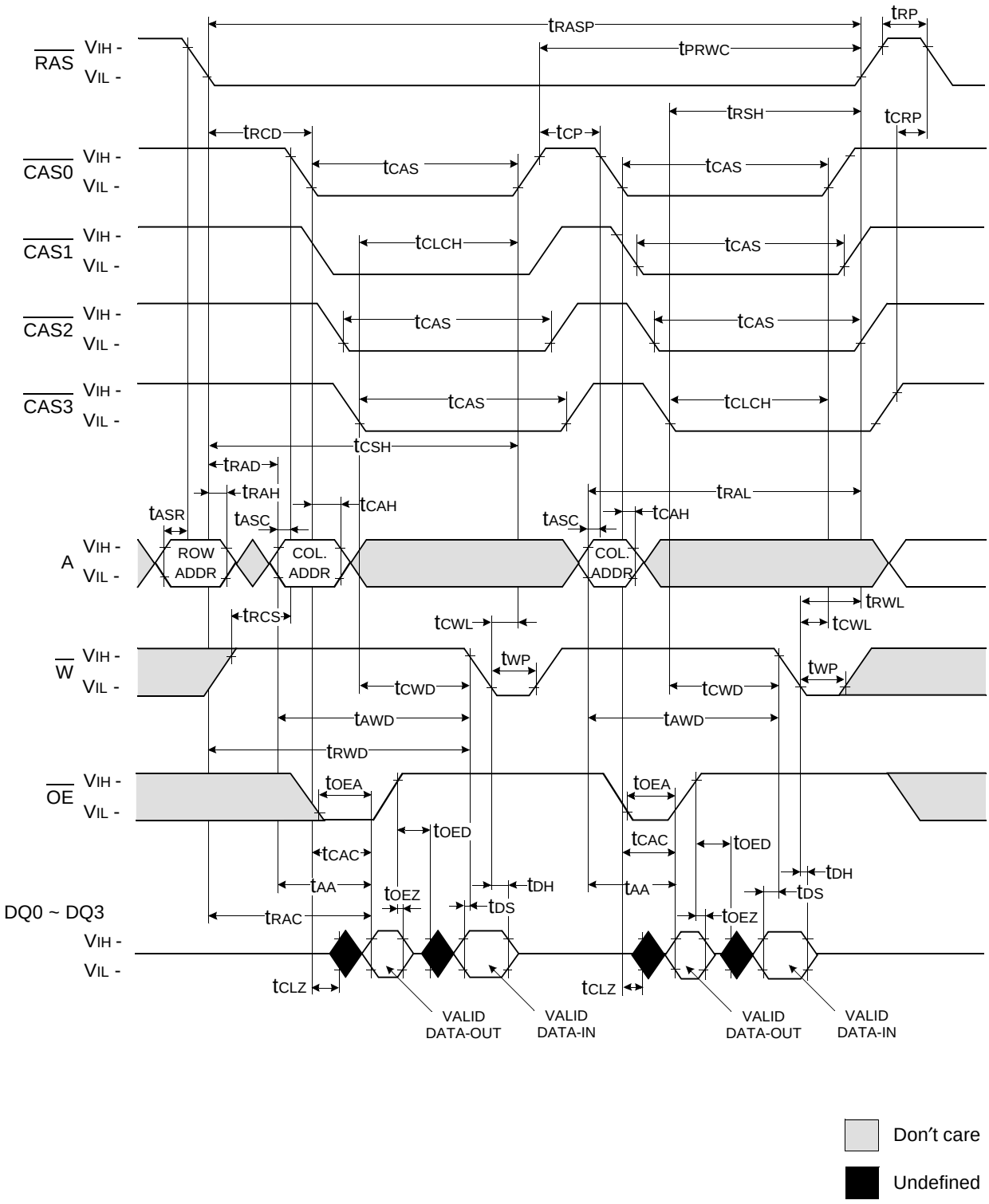


HYPER PAGE MODE WRITE CYCLE (EARLY WRITE)

NOTE : DOUT = OPEN



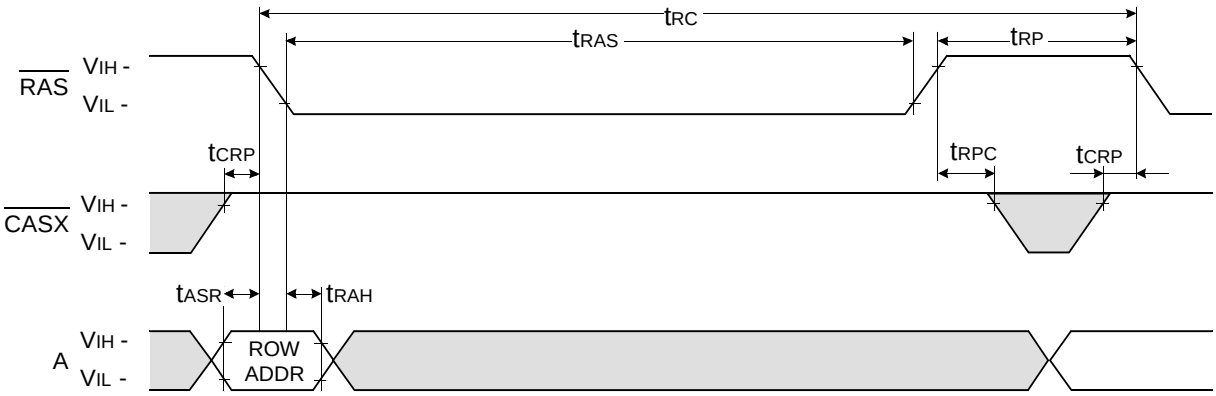
HYPER PAGE READ - MODIFY - WRITE CYCLE



$\overline{RAS}$ - ONLY REFRESH CYCLE*

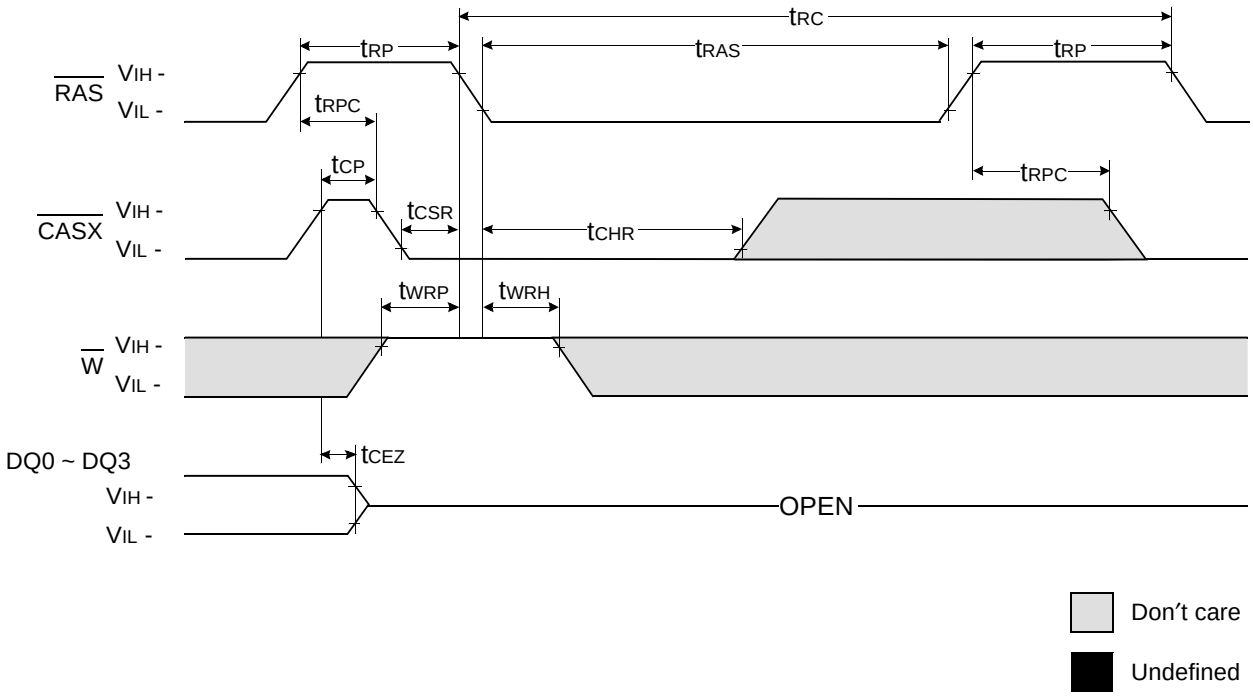
NOTE : $\overline{W}$, $\overline{OE}$, D_{IN} = Don't care

D_{OUT} = OPEN

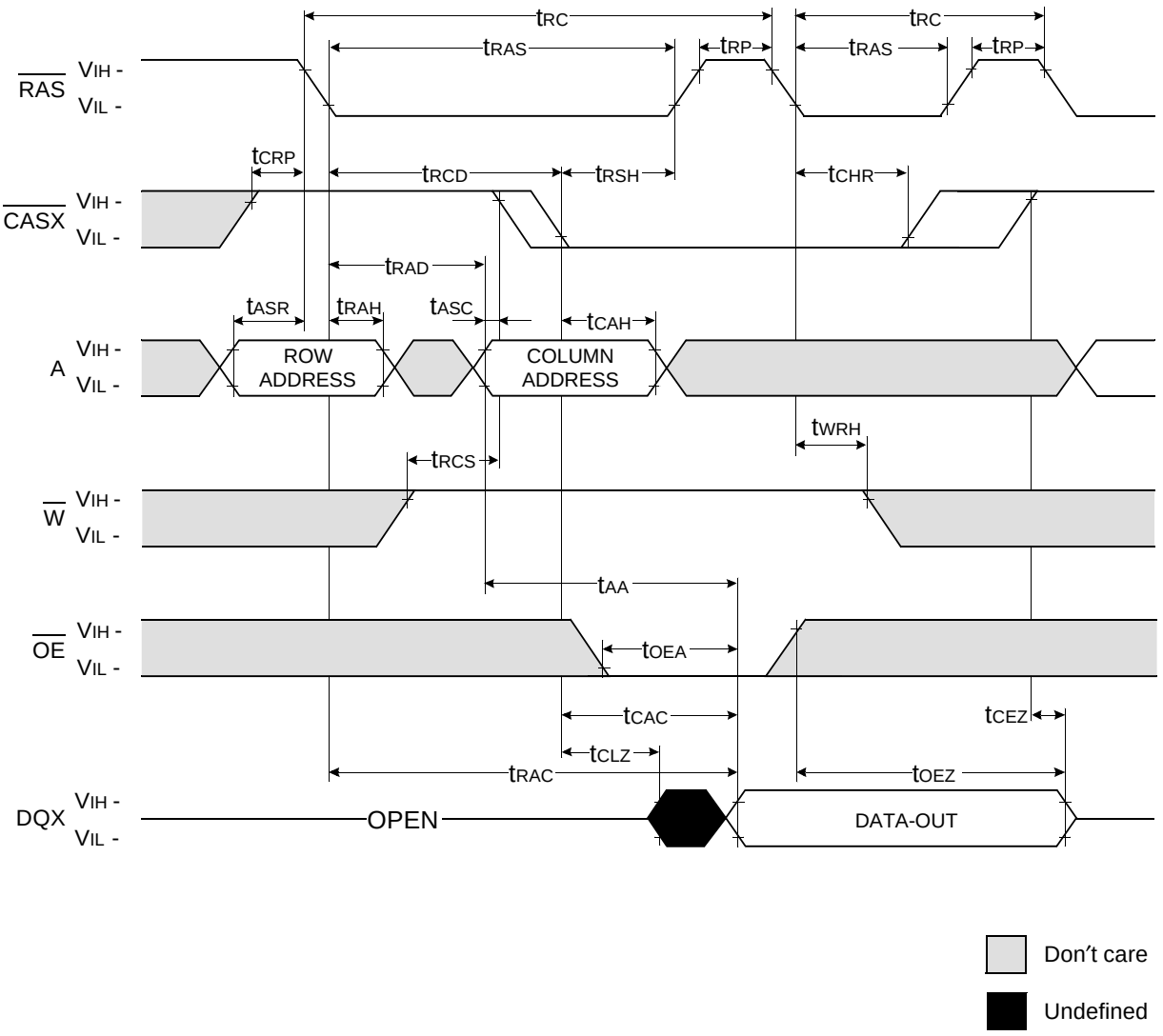


$\overline{CAS}$ - BEFORE - $\overline{RAS}$ REFRESH CYCLE

NOTE : $\overline{OE}$, A = Don't care

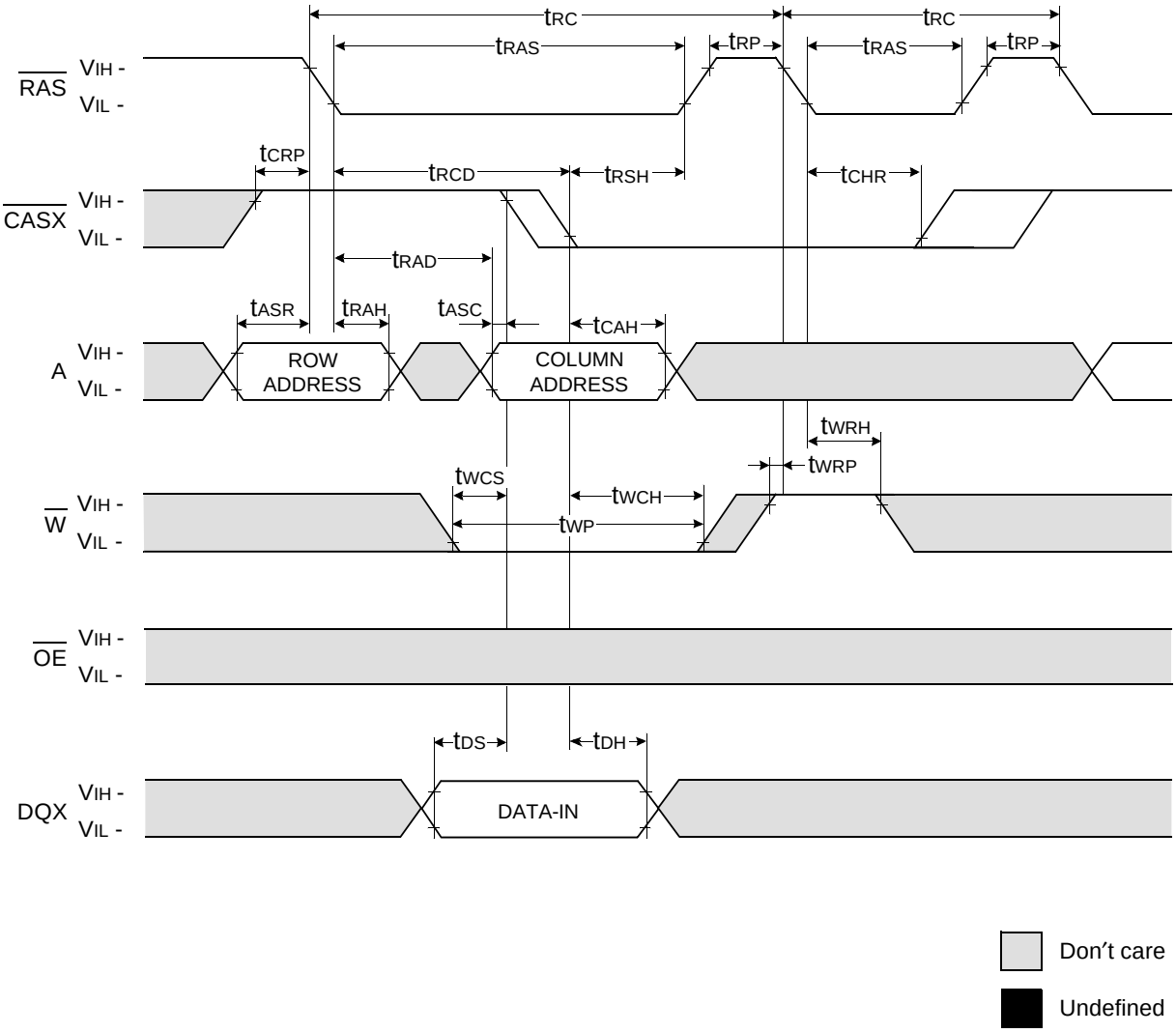


HIDDEN REFRESH CYCLE (READ)

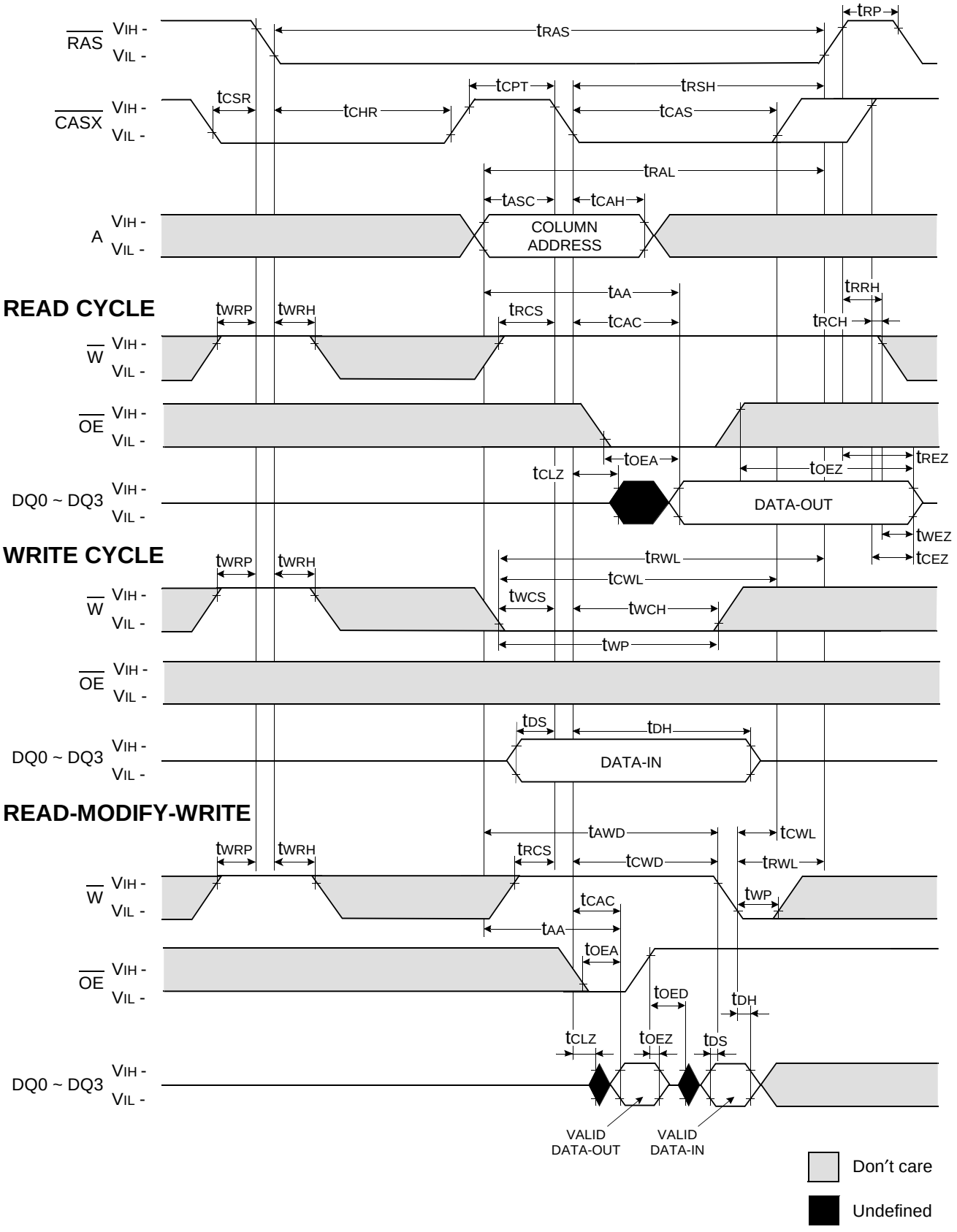


HIDDEN REFRESH CYCLE (WRITE)

NOTE : DOUT = OPEN

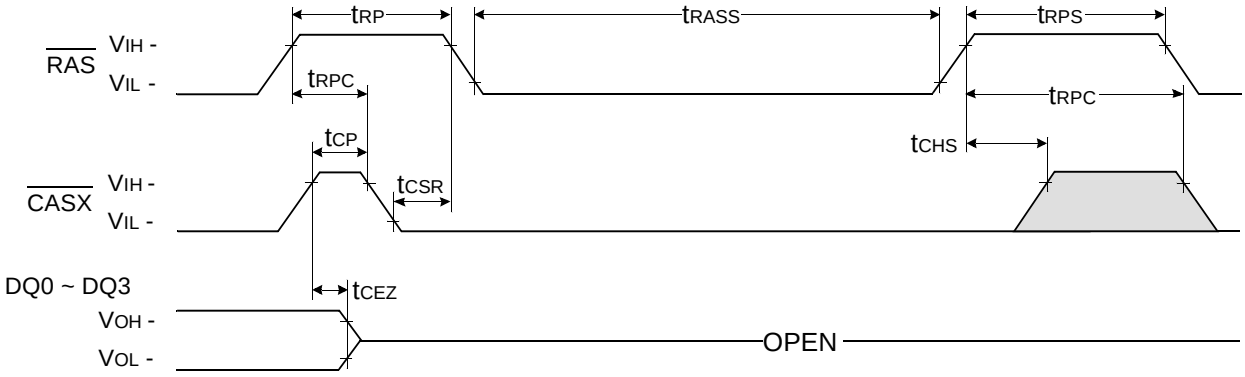


CAS-BEFORE-RAS REFRESH COUNTER TEST CYCLE



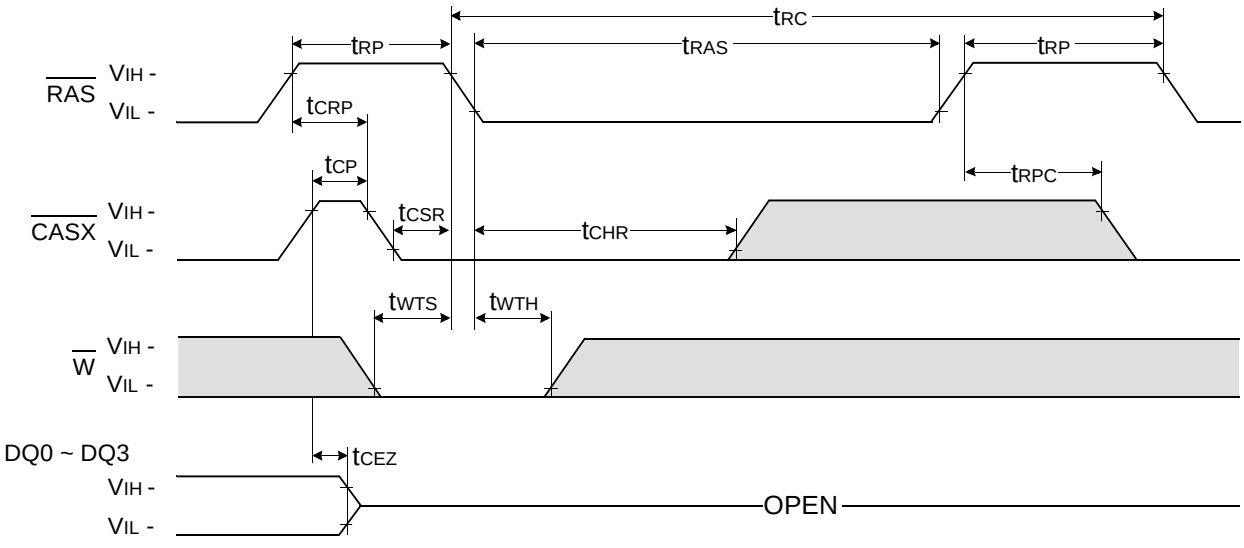
$\overline{CAS}$ - BEFORE - $\overline{RAS}$ SELF REFRESH CYCLE

NOTE : $\overline{OE}$, A = Don't care, $\overline{WE}$=Vcc-0.2V



TEST MODE IN CYCLE

NOTE : $\overline{OE}$, A = Don't care



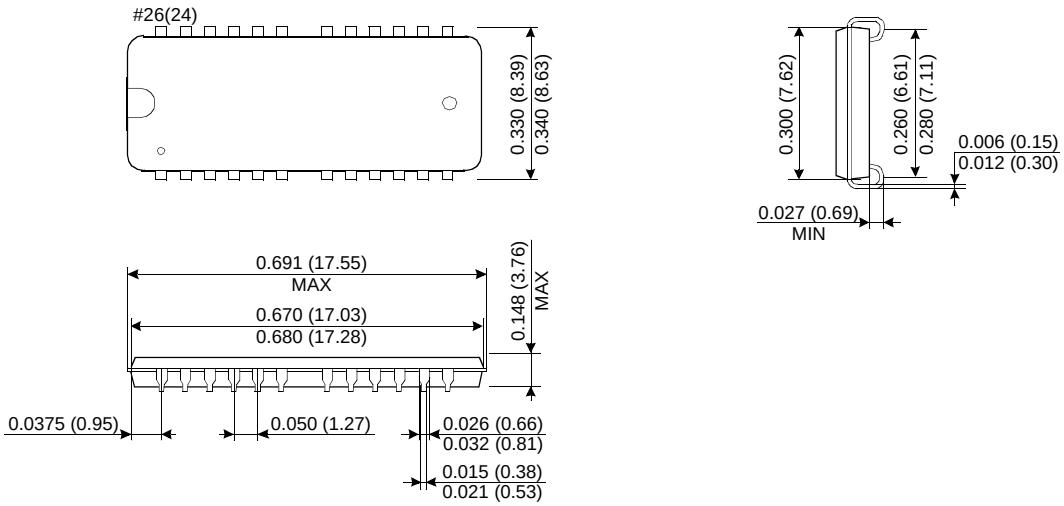
Don't care

Undefined

PACKAGE DIMENSON

26(24) SOJ 300mil

Units : Inches (millimeters)



26(24) TSOP(II) 300mil

Units : Inches (millimeters)